









### TLV172, TLV2172, TLV4172

SBOS784C-NOVEMBER 2016-REVISED JANUARY 2019

# TLVx172 36-V, single-supply, low-power operational amplifier for cost-sensitive systems

### 1 Features

- Supply Range: 4.5 V to 36 V, ±2.25 V to ±18 V
- Low Noise: 9 nV/√Hz
- Low Offset Drift: ±1 μV/°C (Typical)
- EMI-Hardened
- Input Range Includes Negative Supply
- Rail-to-Rail Output
- Gain Bandwidth: 10 MHz
- Slew Rate: 10 V/μs
- Low Quiescent Current: 1.6 mA per Amplifier
- High Common-Mode Rejection: 116 dB (Typical)
- Low Input Bias Current: 10 pA

# 2 Applications

- TFT-LCD Drive Circuits
- Touch-Screen Displays
- Wireless LANs
- Portable Instrumentation
- Analog-to-Digital Converter (ADC) Buffers
- Active Filters
- Line Drivers or Line Receivers
- Ultrasound
- Currency Counters
- Transducer Amplifiers

# 3 Description

The TLVx172 family of electromagnetic interference (EMI)-hardened, 36-V, single-supply, low-noise operational amplifiers (op amps) features a THD+N of 0.0002% at 1 kHz with the ability to operate on supplies ranging from 4.5 V (±2.25 V) to 36 V (±18V). These features, along with low noise and very high PSRR, enable the TLVx172 to amplify microvolt-level signals in applications such as HEV and EV automobiles and power medical trains. instrumentation, and more. The TLVx172 device offers good offset and drift, a high bandwidth of 10 MHz, and a slew rate of 10 V/µs with only 2.3 mA of quiescent current over temperature (maximum).

Unlike most op amps that are specified at only one supply voltage, the TLVx172 device is specified from 4.5 V to 36 V. Input signals beyond the supply rails do not cause phase reversal. TLVx172 device is stable with capacitive loads up to 300 pF. The input can operate 100 mV below the negative rail and within 2 V of the positive rail for normal operation. Note that the device can operate with a full rail-to-rail input 100 mV beyond the positive rail, but with reduced performance within 2 V of the positive rail.

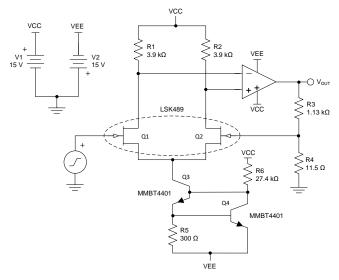
The TLVx172 op amp is specified from  $-40^{\circ}$ C to  $+125^{\circ}$ C.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)	
	SOIC (8)	4.90 mm × 3.91 mm	
TLV172	SC70 (5)	2.00 mm × 1.25 mm	
	SOT-23 (5)	2.90 mm × 1.60 mm	
TLV2172	SOIC (8)	4.90 mm × 3.91 mm	
ILV2172	VSSOP (8)	3.00 mm × 3.00 mm	
TLV4172	SOIC (14)	8.65 mm × 3.91 mm	
1241/2	TSSOP (14)	5.00 mm × 4.40 mm	

(1) For all available packages, see the orderable addendum at the end of the data sheet.

#### Simplified Schematic



2

# **Table of Contents**

9

12.3

12.4

13

1	Feat	tures 1
2	Арр	lications 1
3	Des	cription 1
4	Rev	ision History 2
5	Dev	ice Comparison Table 3
6	Pin	Configuration and Functions 4
7	Spe	cifications7
	7.1	Absolute Maximum Ratings 7
	7.2	ESD Ratings7
	7.3	Recommended Operating Conditions
	7.4	Thermal Information: TLV172 8
	7.5	Thermal Information: TLV2172 8
	7.6	Thermal Information: TLV4172 8
	7.7	Electrical Characteristics9
	7.8	Typical Characteristics 10
8	Deta	ailed Description 15
	8.1	Overview 15
	8.2	Functional Block Diagram 15
	8.3	Feature Description 16

# 4 Revision History

Changes from Revision B (September 2018) to Revision C				
	anged the datasheet title From: TLV2172 36-V, Single-Supply, Low-Power To: TLVx172 36-V, single- -power			
Change	es from Revision A (May 2018) to Revision B	Page		
• Dele	eted the Device Family Comparison table	3		
• Add	ded the 5-pin SC70 and SOT-23, and the 8-pin SOIC pinout diagrams to the data sheet	4		
• Add	ded TLV172 Pin Functions table to the data sheet	4		

# Changes from Original (November 2016) to Revision A

ISTRUMENTS

EXAS

8.4 Device Functional Modes...... 19 Application and Implementation ...... 20

9.1 Application Information...... 20 9.2 Typical Application ..... 20 10 Power Supply Recommendations ...... 22 11 Layout...... 22 11.1 Layout Guidelines ..... 22 11.2 Layout Example ..... 23 12 Device and Documentation Support ...... 24 12.2 Documentation Support ...... 25

> Related Links ..... 25 Receiving Notification of Documentation Updates 25

12.7 Electrostatic Discharge Caution ...... 25 12.8 Glossary ...... 25

Information ...... 26

Mechanical, Packaging, and Orderable

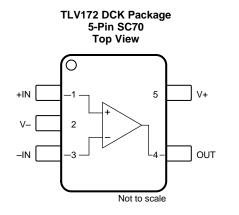
Page

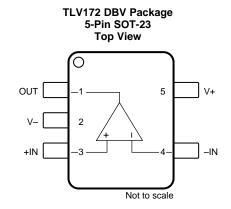


# 5 Device Comparison Table

DEVICE	PACKAGE
TLV172 (single)	SC70-5, SOT-23-5, SOIC-8
TLV2172 (dual)	SOIC-8, VSSOP-8
TLV4172 (quad)	SOIC-14, TSSOP-14

# 6 Pin Configuration and Functions





TLV172 D Package 8-Pin SOIC Top View Ο NC 8 NC 7 V+ –IN 2 +IN 3 -6 OUT V– 5 NC 4

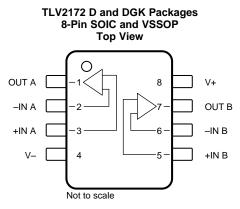
NC- no internal connection

#### Pin Functions: TLV172

Not to scale

PIN			I/O	DESCRIPTION		
NAME	SC70	SOT-23	SOIC	1/0	DESCRIPTION	
–IN	3	4	2	Ι	Negative (inverting) input	
+IN	1	3	3	Ι	Positive (noninverting) input	
NC	—	—	1, 5, 8		No internal connection (can be left floating)	
OUT	4	1	6	0	Output	
V–	2	2	4		Negative (lowest) power supply	
V+	5	5	7		Positive (highest) power supply	





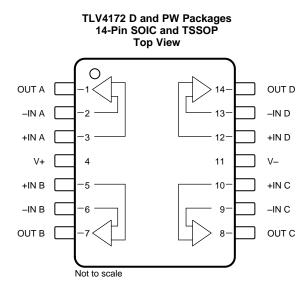
#### Pin Functions: TLV2172

	PIN			DESCRIPTION	
NAME	SOIC (D)	VSSOP (DGK)	I/O		
–IN A	2	2	I	Inverting input, channel A	
–IN B	6	6	I	Inverting input, channel B	
+IN A	3	3	I	Noninverting input, channel A	
+IN B	5	5	I	Noninverting input, channel B	
OUT A	1	1	0	Output, channel A	
OUT B	7	7	0	Output, channel B	
V–	4	4	_	Negative (lowest) power supply	
V+	8	8		Positive (highest) power supply	

#### TLV172, TLV2172, TLV4172 SBOS784C – NOVEMBER 2016 – REVISED JANUARY 2019



www.ti.com



#### Pin Functions: TLV4172

	PIN			DESCRIPTION	
NAME	SOIC (D)	TSSOP (PW)	I/O		
–IN A	2	2	I	Inverting input, channel A	
–IN B	6	6	I	Inverting input, channel B	
–IN C	9	9	I	Inverting input, channel C	
–IN D	13	13	I	Inverting input, channel D	
+IN A	3	3	I	Noninverting input, channel A	
+IN B	5	5	I	Noninverting input, channel B	
+IN C	10	10	I	Noninverting input, channel C	
+IN D	12	12	I	Noninverting input, channel D	
OUT A	1	1	0	Output, channel A	
OUT B	7	7	0	Output, channel B	
OUT C	8	8	0	Output, channel C	
OUT D	14	14	0	Output, channel D	
V–	11	11	_	Negative (lowest) power supply	
V+	4	4	—	Positive (highest) power supply	

Submit Documentation Feedback

6

Copyright © 2016–2019, Texas Instruments Incorporated



### 7 Specifications

### 7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT
	Supply voltage, [(V+) – (V–)]			40	
Valtaga	Single-supply voltage			40	V
Voltage	Signal input pin <sup>(2)</sup>	Common-mode	(V–) – 0.5	(V+) + 0.5	-
		Differential <sup>(3)</sup>	-0.5	0.5	
Current	Signal input pin		-10	10	mA
Current	Output short-circuit <sup>(4)</sup>		Continue	ous	
Temperature	Operating, T <sub>A</sub>		-55	150	
	Junction, $T_J$			150	°C
	Storage, T <sub>stg</sub>		-65	150	

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) Transient conditions that exceed these voltage ratings must be current limited to 10 mA or less.

(3) See the *Electrical Overstress* section for more information.

(4) Short-circuit to ground, one amplifier per package.

#### 7.2 ESD Ratings

			VALUE	UNIT
V	Electrostatio discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±4000	V
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±1000	v

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

#### 7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT	
Supply voltage, (V+) – (V–)	Single-supply	4.5	36		
	Dual-supply	±2.25	±18	V	
Specified temperature		-40	125	°C	

### TLV172, TLV2172, TLV4172

SBOS784C-NOVEMBER 2016-REVISED JANUARY 2019

STRUMENTS

XAS

### 7.4 Thermal Information: TLV172

			TLV172			
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	DBV (SOT-23)	DCK (SC70)	UNIT	
		8 PINS	5 PINS	5 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	126.5	227.9	285.2	°C/W	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	80.6	115.7	60.5	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	67.1	65.9	78.9	°C/W	
ΨJT	Junction-to-top characterization parameter	31.0	10.7	0.8	°C/W	
ΨЈВ	Junction-to-board characterization parameter	65.6	65.3	77.9	°C/W	
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	—	_	_	°C/W	

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

### 7.5 Thermal Information: TLV2172

		TLV		
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	DGK (VSSOP)	UNIT
		8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	116.1	158	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	69.8	48.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	56.6	78.7	°C/W
ΨJT	Junction-to-top characterization parameter	22.5	3.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	56.1	77.3	°C/W
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	_	_	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

### 7.6 Thermal Information: TLV4172

		TLV4172				
	THERMAL METRIC <sup>(1)</sup>	D (SOIC)	PW (TSSOP)	UNIT		
		14 PINS	14 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	82.7	111.1	°C/W		
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	42.3	40.8	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	37.3	54.1	°C/W		
ΨJT	Junction-to-top characterization parameter	8.9	3.8	°C/W		
ΨJB	Junction-to-board characterization parameter	37	53.3	°C/W		
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	—	—	°C/W		

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

# 7.7 Electrical Characteristics

at $T_A = 25^{\circ}C$ , $V_S = \pm 2.25$ V to $\pm 18$ V	, $V_{CM} = V_{OUT} = V_S$ / 2, and $R_L = 10 \text{ k}\Omega$ co	onnected to V <sub>S</sub> / 2 (unless otherwise noted)
---	---	---

	PARAMETER	TEST CON	DITIONS	MIN	TYP	MAX	UNIT
OFFSET	VOLTAGE						
.,		T <sub>A</sub> = 25°C			0.5	1.7	
V <sub>OS</sub>	Input offset voltage	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$				2	mV
dV <sub>OS</sub> /dT	Input offset voltage drift	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$		1		µV/°C	
PSRR	Power-supply rejection ratio	$V_{\rm S} = 4$ V to 36 V, $T_{\rm A} = -40^{\circ}$ C to +12	25°C	100	120		dB
	Channel separation, dc				5		μV/V
INPUT B	IAS CURRENT						
IB	Input bias current	T <sub>A</sub> = 25°C			±10		pА
l <sub>os</sub>	Input offset current	$T_A = 25^{\circ}C$			±2		pA
NOISE	•						
	Input voltage noise	f = 0.1 Hz to 10 Hz			2.5		μV <sub>PP</sub>
		f = 100 Hz			14		nV/√Hz
e <sub>n</sub>	Input voltage noise density	f = 1 kHz			9		nV/√Hz
in	Input current noise density	f = 1  kHz			1.6		fA/√Hz
	OLTAGE				1.0		17 4 11 12
-				(V–) –			
V <sub>CM</sub>	Common-mode voltage range <sup>(1)</sup>			0.1		(V+) – 2	V
CMRR	Common-mode rejection ratio	$V_{S} = \pm 18 \text{ V}, (V-) - 0.1 \text{ V} < V_{CM} < (V-) T_{A} = -40^{\circ}\text{C} \text{ to } +125^{\circ}\text{C}$	/+) – 2 V,	94	116		dB
	<b>MPEDANCE</b>	L		4		ļ	
	Differential				100    4		MΩ    pF
	Common-mode				6    4		10 <sup>13</sup> Ω    pF
OPEN-I	OOP GAIN						μ.
0. 2.1 2.		(V−) + 0.35 V < V <sub>Ω</sub> < (V+) − 0.35 V	$T_{A} = -40^{\circ}C$ to +125°C	97	115		
A <sub>OL</sub> Open-loop voltage gain		$(V-) + 0.5 V < V_0 < (V+) - 0.5 V,$	51	110		dB	
		$R_L = 2 k\Omega, T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		107			
FREQUE	NCY RESPONSE						
GBP	Gain bandwidth product				10		MHz
SR	Slew rate	G = +1			10		V/µs
		To 0.1%, V <sub>S</sub> = ±18 V, G = +1, 10-V	step		2		
t <sub>S</sub>	Settling time	To 0.01% (12-bit), V <sub>S</sub> = ±18 V, G =	+1, 10-V step		3.2		μs
	Overload recovery time	V <sub>IN</sub> × gain > V <sub>S</sub>			200		ns
THD+N	Total harmonic distortion + noise	V <sub>S</sub> = 36 V, G = +1, f = 1 kHz, V <sub>O</sub> =	0	0.0002%			
OUTPUT	-		1400				
			T <sub>A</sub> = 25°C		70		
		$V_{S} = \pm 18 \text{ V}, \text{ R}_{L} = 10 \text{ k}\Omega$	$T_{A} = -40^{\circ}C \text{ to } +125^{\circ}C$	°C	95		
Vo	Voltage output swing from rail		T <sub>A</sub> = 25°C		330	400	mV
	$V_{S} = \pm 18 \text{ V}, \text{ R}_{L} = 2 \text{ k}\Omega$	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$	°C	470	530		
I <sub>SC</sub>	Short-circuit current				±75		mA
CLOAD	Capacitive load drive			See Typic		teristics	pF
CLOAD	Open-loop output resistance	f = 1 MHz, I <sub>O</sub> = 0 A			60		Ω
Ro		1 - 1 $10 - 0$			00		22
R <sub>0</sub>		-					
	SUPPLY Specified voltage range			4.5		36	V

The input range can be extended beyond (V+) – 2 V up to V+. See the *Typical Characteristics* and *Application and Implementation* sections for additional information.



### 7.8 Typical Characteristics

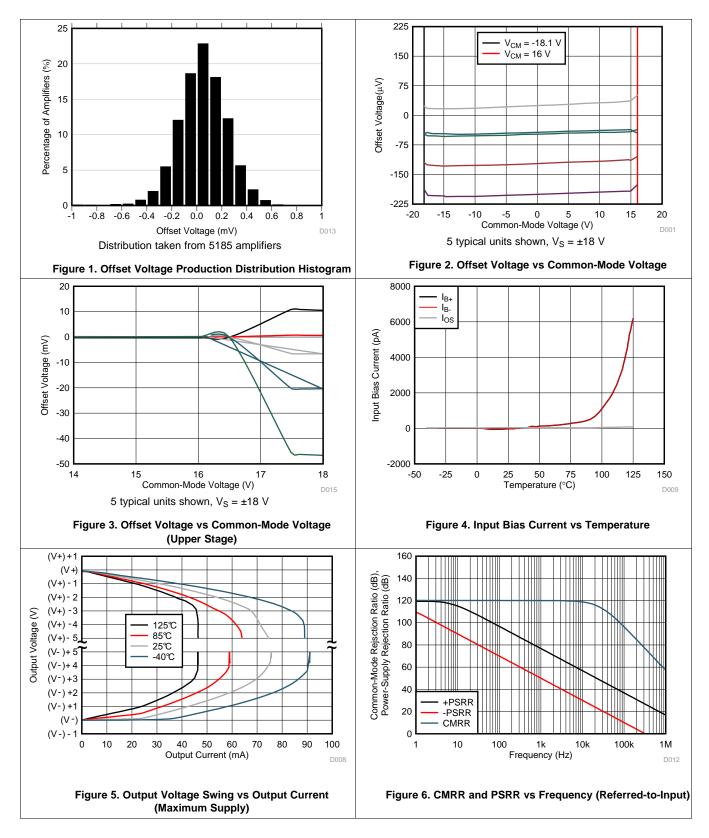
at V<sub>S</sub> = ±18 V, V<sub>CM</sub> = V<sub>S</sub> / 2, R<sub>LOAD</sub> = 10 k $\Omega$  connected to V<sub>S</sub> / 2, and C<sub>L</sub> = 100 pF (unless otherwise noted)

### Table 1. Characteristic Performance Measurements

DESCRIPTION	FIGURE
Offset Voltage Production Distribution	Figure 1
Offset Voltage vs Common-Mode Voltage	Figure 2
Offset Voltage vs Common-Mode Voltage (Upper Stage)	Figure 3
Input Bias Current vs Temperature	Figure 4
Output Voltage Swing vs Output Current (Maximum Supply)	Figure 5
CMRR and PSRR vs Frequency (Referred-to-Input)	Figure 6
0.1-Hz to 10-Hz Noise	Figure 7
Input Voltage Noise Spectral Density vs Frequency	Figure 8
Quiescent Current vs Supply Voltage	Figure 9
Open-Loop Gain and Phase vs Frequency	Figure 10
Closed-Loop Gain vs Frequency	Figure 11
Open-Loop Output Impedance vs Frequency	Figure 12
Small-Signal Overshoot vs Capacitive Load	Figure 13, Figure 14
No Phase Reversal	Figure 15
Small-Signal Step Response (10 mV)	Figure 16, Figure 17
Large-Signal Step Response	Figure 18, Figure 19
Large-Signal Settling Time	Figure 20, Figure 21
Short-Circuit Current vs Temperature	Figure 22
Maximum Output Voltage vs Frequency	Figure 23
EMIRR IN+ vs Frequency	Figure 24



#### at V<sub>S</sub> = ±18 V, V<sub>CM</sub> = V<sub>S</sub> / 2, R<sub>LOAD</sub> = 10 k $\Omega$ connected to V<sub>S</sub> / 2, and C<sub>L</sub> = 100 pF (unless otherwise noted)

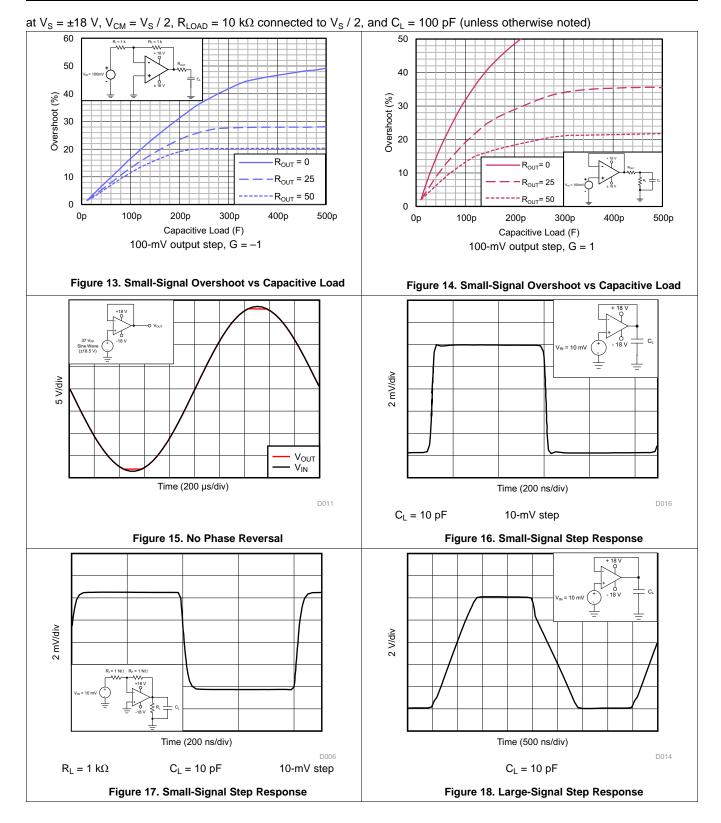


TLV172, TLV2172, TLV4172 SBOS784C-NOVEMBER 2016-REVISED JANUARY 2019

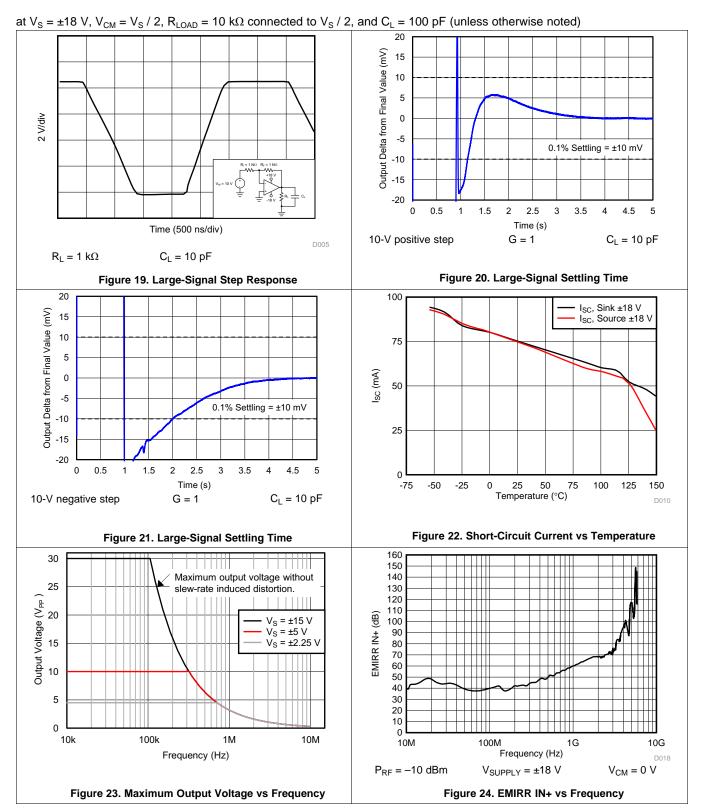
www.ti.com

#### at V<sub>S</sub> = ±18 V, V<sub>CM</sub> = V<sub>S</sub> / 2, R<sub>LOAD</sub> = 10 k $\Omega$ connected to V<sub>S</sub> / 2, and C<sub>L</sub> = 100 pF (unless otherwise noted) Noise Spectral Density (n//rtHz) 00 01 1μV/div 1 10 100 1k 100k 1 10k Time (1s/div) G013 Frequency (Hz) Figure 7. 0.1-Hz to 10-Hz Noise Figure 8. Input Voltage Noise Spectral Density vs Frequency 140 180 1.8 Open-Loop Gain 1.7 120 Phase 100 135 Quiescent Current (mA) 1.6 1.5 80 0 Gain (dB) Phase ( 1.4 60 90 1.3 40 1.2 20 45 ÷ 1.1 0 -20 0 4 8 16 20 28 10 100 10M 0 12 24 32 36 1k 10k 100k 1M 1 Supply Voltage (V) Frequency (Hz) D007 D004 $C_{LOAD} = 15 \text{ pF}$ Figure 9. Quiescent Current vs Supply Voltage Figure 10. Open-Loop Gain and Phase vs Frequency 100 25 20 15 10 10 Gain (dB) 5 Z<sub>0</sub> (Ω) 0 -5 -10 G = +1 -15 G = -10 G = -1 -20 1000 10k 100k 1M 10M 10 100 1k 10k 100k 1M 10M 100M Frequency (Hz) Frequency (Hz) D017 Figure 11. Closed-Loop Gain vs Frequency





SBOS784C-NOVEMBER 2016-REVISED JANUARY 2019



www.ti.com

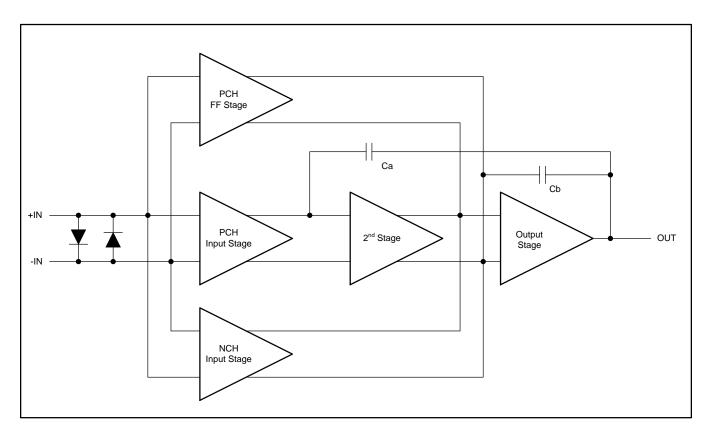


### 8 Detailed Description

#### 8.1 Overview

The TLVx172 operational amplifier provides high overall performance, making these devices designed for many general-purpose applications. The excellent offset drift of only 1  $\mu$ V/°C provides excellent stability over the entire temperature range. In addition, the device offers very good overall performance with high CMRR, PSRR, and A<sub>OL</sub>.

### 8.2 Functional Block Diagram





#### 8.3 Feature Description

#### 8.3.1 Operating Characteristics

The TLVx172 amplifier is specified for operation from 4.5 V to 36 V ( $\pm$ 2.25 V to  $\pm$ 18 V). Many of the specifications apply from -40°C to +125°C. Parameters that can exhibit significant variance with regard to operating voltage or temperature are shown in the *Typical Characteristics* section.

#### 8.3.2 Phase-Reversal Protection

The TLVx172 device has an internal phase-reversal protection. Many operational amplifiers exhibit a phase reversal when the input is driven beyond the linear common-mode range. This condition is most often encountered in noninverting circuits when the input is driven beyond the specified common-mode voltage range, causing the output to reverse into the opposite rail. The input of the TLVx172 prevents phase reversal with excessive common-mode voltage. Instead, the output limits into the appropriate rail. This performance is shown in Figure 25.

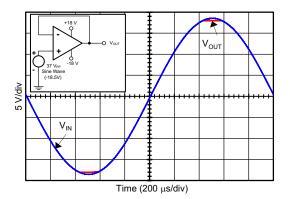


Figure 25. No Phase Reversal

#### 8.3.3 Electrical Overstress

Designers often ask questions about the capability of an operational amplifier to withstand electrical overstress. These questions tend to focus on the device inputs, but can involve the supply voltage pins or even the output pin. Each of these different pin functions have electrical stress limits determined by the voltage breakdown characteristics of the particular semiconductor fabrication process and specific circuits connected to the pin. Additionally, internal electrostatic discharge (ESD) protection is built into these circuits for protection from accidental ESD events both before and during product assembly.

A good understanding of this basic ESD circuitry and the relevance to an electrical overstress event is helpful. Figure 26 shows the ESD circuits contained in the TLVx172 (indicated by the dashed box). The ESD protection circuitry involves several current-steering diodes connected from the input and output pins and routed back to the internal power-supply lines, where the diodes meet at an absorption device internal to the operational amplifier. This protection circuitry is intended to remain inactive during normal circuit operation.



#### Feature Description (continued)

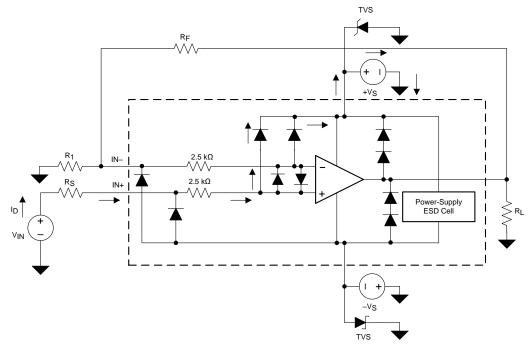


Figure 26. Equivalent Internal ESD Circuitry Relative to a Typical Circuit Application

An ESD event produces a short-duration, high-voltage pulse that is transformed into a short-duration, highcurrent pulse when discharging through a semiconductor device. The ESD protection circuits are designed to provide a current path around the operational amplifier core to prevent damage. The energy absorbed by the protection circuitry is then dissipated as heat.

When an ESD voltage develops across two or more amplifier device pins, current flows through one or more steering diodes. Depending on the path that the current takes, the absorption device can activate. The absorption device has a trigger, or threshold voltage, that is above the normal operating voltage of the TLVx172 but below the device breakdown voltage level. When this threshold is exceeded, the absorption device quickly activates and clamps the voltage across the supply rails to a safe level.

When the operational amplifier connects into a circuit, as shown in Figure 26, the ESD protection components are intended to remain inactive and do not become involved in the application circuit operation. However, circumstances can arise where an applied voltage exceeds the operating voltage range of a given pin. If this condition occurs, there is a risk that some internal ESD protection circuits can turn on and conduct current. Any such current flow occurs through steering-diode paths and rarely involves the absorption device.

Figure 26 shows a specific example where the input voltage ( $V_{IN}$ ) exceeds the positive supply voltage (V+) by 500 mV or more. Much of what happens in the circuit depends on the supply characteristics. If V+ can sink the current, then one of the upper input steering diodes conducts and directs current to V+. Excessively high current levels can flow with increasingly higher  $V_{IN}$ . As a result, the data sheet specifications recommend that applications limit the input current to 10 mA.

If the supply is not capable of sinking the current,  $V_{IN}$  can begin sourcing current to the operational amplifier and then take over as the source of positive supply voltage. The danger in this case is that the voltage can rise to levels that exceed the operational amplifier absolute maximum ratings.

Another common question involves what happens to the amplifier if an input signal is applied to the input when the power supplies (V+ or V–) are at 0 V. Again, this question depends on the supply characteristic when at 0 V, or at a level below the input signal amplitude. If the supplies appear as high impedance, then the input source supplies the operational amplifier current through the current-steering diodes. This state is not a normal bias condition; most likely, the amplifier does not operate normally. If the supplies are low impedance, then the current through the steering diodes can become quite high. The current level depends on the ability of the input source to deliver current and any resistance in the input path.



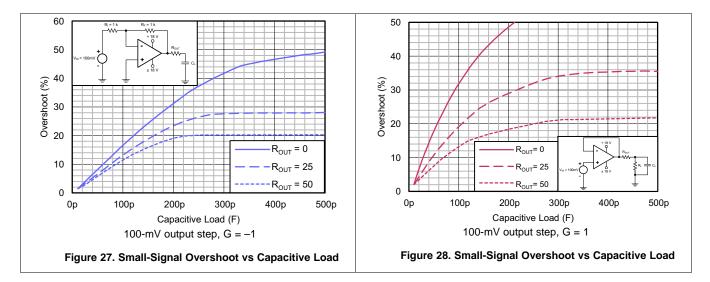
#### Feature Description (continued)

If there is any uncertainty about the ability of the supply to absorb this current, add external Zener diodes to the supply pins; see Figure 26. Select the Zener voltage so that the diode does not turn on during normal operation. However, the Zener voltage must be low enough so that the Zener diode conducts if the supply pin begins to rise above the safe-operating, supply-voltage level.

The input pins of the TLVx172 are protected from excessive differential voltage with back-to-back diodes; see Figure 26. In most circuit applications, the input protection circuitry has no effect. However, in low-gain or G = 1 circuits, fast-ramping input signals can forward-bias these diodes because the output of the amplifier cannot respond rapidly enough to the input ramp. If the input signal is fast enough to create this forward-bias condition, then limit the input signal current to 10 mA or less. If the input signal current is not inherently limited, an input series resistor can limit the input signal current. This input series resistor degrades the low-noise performance of the TLVx172. Figure 26 shows an example configuration that implements a current-limiting feedback resistor.

#### 8.3.4 Capacitive Load and Stability

The dynamic characteristics of the TLVx172 are optimized for common operating conditions. The combination of low closed-loop gain and high capacitive loads decreases the phase margin of the amplifier and can lead to gain peaking or oscillations. As a result, heavier capacitive loads must be isolated from the output. The simplest way to achieve this isolation is to add a small resistor (for example,  $R_{OUT}$  equal to 50  $\Omega$ ) in series with the output. Figure 27 and Figure 28 show graphs of small-signal overshoot versus capacitive load for several values of  $R_{OUT}$ . See the *Feedback Plots Define Op Amp AC Performance* application note for details of analysis techniques and application circuits.





#### 8.4 Device Functional Modes

#### 8.4.1 Common-Mode Voltage Range

The input common-mode voltage range of the TLVx172 device extends 100 mV below the negative rail and within 2 V of the top rail for normal operation.

This device can operate with full rail-to-rail input 100 mV beyond the top rail, but with reduced performance within 2 V of the top rail. Table 2 lists the typical performances in this range.

PARAMETER	MIN	ТҮР	MAX	UNIT
Input common-mode voltage	(V+) − 2		(V+) + 0.1	V
Offset voltage		7		mV
Offset voltage vs temperature		12		μV/°C
Common-mode rejection		65		dB
Open-loop gain		60		dB
Gain-bandwidth product		0.3		MHz
Slew rate		0.3		V/µs

Table 2. Typical Performance for Common-Mode Voltages Within 2 V of the Positive Supply

#### 8.4.2 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from the saturated state to the linear state. The output devices of the operational amplifier enter the saturation region when the output voltage exceeds the rated operating voltage, which is a result from the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return back to the normal state. After the charge carriers return back to the equilibrium state, the device begins to slew at the normal slew rate. As a result, the propagation delay in case of an overload condition is the sum of the overload recovery time and the slew time. The overload recovery time for the TLVx172 is approximately 2 µs.

Texas Instruments

www.ti.com

### 9 Application and Implementation

#### NOTE

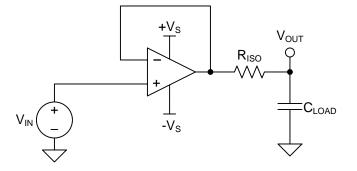
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 9.1 Application Information

The TLVx172 operational amplifier provides high overall performance in a large number of general-purpose applications. As with all amplifiers, applications with noisy or high-impedance power supplies require decoupling capacitors placed close to the device pins. In most cases, 0.1-µF capacitors are adequate. Follow the additional recommendations in the *Layout Guidelines* section to achieve the maximum performance from this device. Many applications introduce capacitive loading to the output of the amplifier (which potentially causes instability). To stabilize the amplifier, add an isolation resistor between the amplifier output and the capacitive load. *Typical Application* section shows the process for selecting a resistor.

#### 9.2 Typical Application

This circuit can drive capacitive loads (such as cable shields, reference buffers, MOSFET gates, and diodes). The circuit uses an isolation resistor ( $R_{ISO}$ ) to stabilize the output of an operational amplifier.  $R_{ISO}$  modifies the open-loop gain of the system to ensure that the circuit has sufficient phase margin.



Copyright © 2017, Texas Instruments Incorporated

Figure 29. Unity-Gain Buffer With R<sub>ISO</sub> Stability Compensation

#### 9.2.1 Design Requirements

The design requirements are:

- Supply voltage: 30 V (±15 V)
- Capacitive loads: 100 pF, 1000 pF, 0.01  $\mu$ F, 0.1  $\mu$ F, and 1  $\mu$ F
- Phase margin: 45° and 60°

#### 9.2.2 Detailed Design Procedure

Figure 29 shows a unity-gain buffer driving a capacitive load. Equation 1 shows the transfer function for the circuit in Figure 29. Figure 29 does not show the open-loop output resistance of the operational amplifier ( $R_0$ ).

$$T(s) = \frac{1 + C_{LOAD} \times R_{ISO} \times s}{1 + (R_o + R_{ISO}) \times C_{LOAD} \times s}$$

The transfer function in Equation 1 has a pole and a zero. The frequency of the pole ( $f_p$ ) is determined by ( $R_o + R_{ISO}$ ) and  $C_{LOAD}$ . The  $R_{ISO}$  and  $C_{LOAD}$  components determine the frequency of the zero ( $f_z$ ). A stable system is obtained by selecting  $R_{ISO}$  so that the rate of closure (ROC) between the open-loop gain ( $A_{OL}$ ) and  $1/\beta$  is 20 dB per decade. Figure 30 shows the concept. The  $1/\beta$  curve for a unity-gain buffer is 0 dB.

(1)



### **Typical Application (continued)**

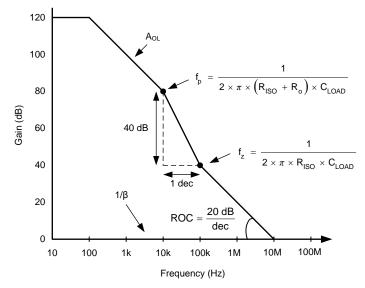


Figure 30. Unity-Gain Amplifier With R<sub>ISO</sub> Compensation

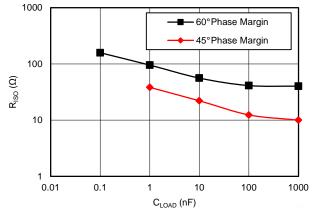
Typically, ROC stability analysis is simulated. The validity of the analysis depends on multiple factors, especially the accurate modeling of  $R_o$ . In addition to simulating the ROC, a robust stability analysis includes a measurement of overshoot percentage and AC gain peaking of the circuit using a function generator, oscilloscope, and gain and phase analyzer. Phase margin is then calculated from these measurements. Table 3 shows the overshoot percentage and AC gain peaking that correspond to phase margins of 45° and 60°. For more details on this design and other alternative devices that can replace the TLVx172, see the *Capacitive Load Drive Solution Using an Isolation Resistor* precision design.

Table 3. Phase Margin	versus Overshoot and AC Gain
•	Peaking

PHASE MARGIN	OVERSHOOT	AC GAIN PEAKING				
45°	23.3%	2.35 dB				
60°	8.8%	0.28 dB				

#### 9.2.3 Application Curve

The values of  $R_{ISO}$  that yield phase margins of 45° and 60° for various capacitive loads are determined using the described methodology. Figure 31 shows the results.







### **10** Power Supply Recommendations

The TLVx172 is specified for operation from 4.5 V to 36 V ( $\pm$ 2.25 V to  $\pm$ 18 V); many specifications apply from  $-40^{\circ}$ C to  $\pm$ 125°C. Parameters that can exhibit significant variance with regard to operating voltage or temperature are shown in the *Typical Characteristics* section.

#### CAUTION

Supply voltages larger than 40 V can permanently damage the device; see the *Absolute Maximum Ratings* table.

Place  $0.1-\mu F$  bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or highimpedance power supplies. For more detailed information on bypass capacitor placement, see the *Layout* section.

### 11 Layout

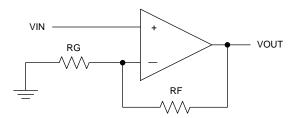
#### 11.1 Layout Guidelines

For best operational performance of the device, use good printed circuit board (PCB) layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and the operational amplifier itself. Bypass capacitors are used to reduce the coupled noise by providing low-impedance power sources local to the analog circuitry.
  - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of the circuitry is one of the simplest and mosteffective methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground planes. A ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise pickup. Make sure to physically separate digital and analog grounds, paying attention to the flow of the ground current.
- In order to reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicularly is much better than in parallel with the noisy trace.
- Place the external components as close to the device as possible. As shown in Figure 33, keeping R<sub>F</sub> and R<sub>G</sub> close to the inverting input minimizes parasitic capacitance.
- Keep the length of input traces as short as possible. Always remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.

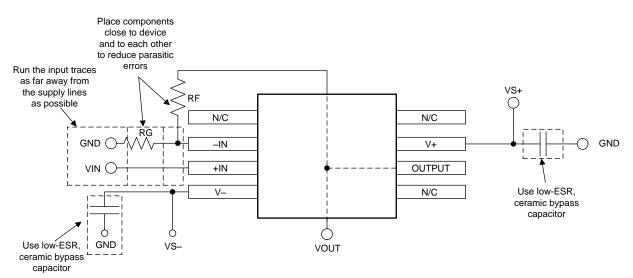


### 11.2 Layout Example



Copyright © 2016, Texas Instruments Incorporated

#### Figure 32. Schematic Representation



Copyright © 2016, Texas Instruments Incorporated

Figure 33. Operational Amplifier Board Layout for a Noninverting Configuration

TEXAS INSTRUMENTS

www.ti.com

### **12 Device and Documentation Support**

#### 12.1 Device Support

#### 12.1.1 Third-Party Products Disclaimer

TI'S PUBLICATION OF INFORMATION REGARDING THIRD-PARTY PRODUCTS OR SERVICES DOES NOT CONSTITUTE AN ENDORSEMENT REGARDING THE SUITABILITY OF SUCH PRODUCTS OR SERVICES OR A WARRANTY, REPRESENTATION OR ENDORSEMENT OF SUCH PRODUCTS OR SERVICES, EITHER ALONE OR IN COMBINATION WITH ANY TI PRODUCT OR SERVICE.

#### 12.1.2 Development Support

#### 12.1.2.1 TINA-TI<sup>™</sup> (Free Software Download)

TINA-TI<sup>™</sup> is a simple, powerful, and easy-to-use circuit simulation program based on a SPICE engine. TINA-TI<sup>™</sup> is a free, fully-functional version of the TINA software, preloaded with a library of macromodels in addition to a range of both passive and active models. TINA-TI<sup>™</sup> provides all the conventional dc, transient, and frequency domain analysis of SPICE, as well as additional design capabilities.

Available as a free download from the Analog eLab Design Center, TINA-TI<sup>™</sup> offers extensive post-processing capability that allows users to format results in a variety of ways. Virtual instruments offer the ability to select input waveforms and probe circuit nodes, voltages, and waveforms, thus creating a dynamic quick-start tool.

#### NOTE

These files require that either the TINA software (from DesignSoft<sup>™</sup>) or the TINA-TI<sup>™</sup> software be installed. Download the free TINA-TI<sup>™</sup> software from the TINA-TI<sup>™</sup> folder.

#### 12.1.2.2 DIP Adapter EVM

The DIP Adapter EVM tool provides an easy, low-cost way to prototype small surface-mount devices. The evaluation tool uses these TI packages: D or U (SOIC-8), PW (TSSOP-8), DGK (VSSOP-8), DBV (SOT23-6, SOT23-5, and SOT23-3), DCK (SC70-6 and SC70-5), and DRL (SOT563-6). The DIP adapter EVM can also be used with terminal strips or can be wired directly to existing circuits.

#### 12.1.2.3 Universal Op Amp EVM

The Universal Op Amp EVM is a series of general-purpose, blank circuit boards that simplify prototyping circuits for a variety of device package types. The evaluation module board design allows many different circuits to be constructed easily and quickly. Five models are offered, with each model intended for a specific package type. PDIP, SOIC, VSSOP, TSSOP, and SOT23 packages are all supported.

#### NOTE

These boards are unpopulated, so users must provide their own devices. TI recommends requesting several op amp device samples when ordering the Universal Op Amp EVM.

#### 12.1.2.4 TI Precision Designs

TI precision designs are analog solutions created by TI's precision analog applications experts and offer the theory of operation, component selection, simulation, a complete PCB schematic and layout, bill of materials, and measured performance of many useful circuits. TI precision designs are available online at www.ti.com/ww/en/analog/precision-designs/.

### 12.1.2.5 WEBENCH<sup>®</sup> Filter Designer

The WEBENCH® Filter Designer is a simple, powerful, and easy-to-use active filter design program. The WEBENCH® Filter Designer allows optimized filter designs to be created by using a selection of TI operational amplifiers and passive components from TI's vendor partners.



#### **Device Support (continued)**

Available as a web-based tool from the WEBENCH® design center, the WEBENCH® filter designer allows complete multistage active filter solutions to be designed, optimized, and simulated within minutes.

#### **12.2** Documentation Support

#### 12.2.1 Related Documentation

For related documentation see the following:

- Feedback Plots Define Op Amp AC Performance
- EMI Rejection Ratio of Operational Amplifiers
- Compensate Transimpedance Amplifiers Intuitively
- Noise Analysis for High-Speed Op Amps

#### 12.3 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to order now.

PARTS	PRODUCT FOLDER	ORDER NOW	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TLV172	Click here	Click here	Click here	Click here	Click here
TLV2172	Click here	Click here	Click here	Click here	Click here
TLV4172	Click here	Click here	Click here	Click here	Click here

#### **Table 4. Related Links**

#### 12.4 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on Alert me to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 12.5 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E<sup>™</sup> Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support TI's Design Support** Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 12.6 Trademarks

TINA-TI, E2E are trademarks of Texas Instruments. WEBENCH is a registered trademark of Texas Instruments. DesignSoft is a trademark of DesignSoft, Inc.

#### 12.7 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### 12.8 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

TLV172, TLV2172, TLV4172

SBOS784C-NOVEMBER 2016-REVISED JANUARY 2019

# 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



10-Dec-2020

# PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TLV172IDBVR	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	18VV	Samples
TLV172IDBVT	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	18VV	Samples
TLV172IDCKR	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	15W	Samples
TLV172IDCKT	ACTIVE	SC70	DCK	5	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	15W	Samples
TLV172IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TLV172	Samples
TLV2172IDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	14P6	Samples
TLV2172IDGKT	ACTIVE	VSSOP	DGK	8	250	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	14P6	Samples
TLV2172IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TL2172	Samples
TLV4172IDR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 125	TLV4172	Samples
TLV4172IPWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TLV4172	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



# PACKAGE OPTION ADDENDUM

10-Dec-2020

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF TLV2172 :

Automotive: TLV2172-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# PACKAGE MATERIALS INFORMATION

www.ti.com

Texas Instruments

### TAPE AND REEL INFORMATION





# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV172IDBVR	SOT-23	DBV	5	3000	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
TLV172IDBVT	SOT-23	DBV	5	250	180.0	8.4	3.23	3.17	1.37	4.0	8.0	Q3
TLV172IDCKR	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TLV172IDCKT	SC70	DCK	5	250	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TLV172IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV2172IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2172IDGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2172IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV4172IDR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
TLV4172IPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

Texas Instruments

www.ti.com

# PACKAGE MATERIALS INFORMATION

30-Dec-2020



*All dimensions are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV172IDBVR	SOT-23	DBV	5	3000	223.0	270.0	35.0
TLV172IDBVT	SOT-23	DBV	5	250	202.0	201.0	28.0
TLV172IDCKR	SC70	DCK	5	3000	180.0	180.0	18.0
TLV172IDCKT	SC70	DCK	5	250	180.0	180.0	18.0
TLV172IDR	SOIC	D	8	2500	853.0	449.0	35.0
TLV2172IDGKR	VSSOP	DGK	8	2500	366.0	364.0	50.0
TLV2172IDGKT	VSSOP	DGK	8	250	366.0	364.0	50.0
TLV2172IDR	SOIC	D	8	2500	853.0	449.0	35.0
TLV4172IDR	SOIC	D	14	2500	853.0	449.0	35.0
TLV4172IPWR	TSSOP	PW	14	2000	853.0	449.0	35.0

# **DBV0005A**



# **PACKAGE OUTLINE**

# SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. Refernce JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.



# DBV0005A

# **EXAMPLE BOARD LAYOUT**

# SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# DBV0005A

# **EXAMPLE STENCIL DESIGN**

# SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

8. Board assembly site may have different recommendations for stencil design.



DCK (R-PDSO-G5)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
  - D. Falls within JEDEC MO-203 variation AA.



# LAND PATTERN DATA



NOTES:

- A. All linear dimensions are in millimeters.B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.

- D Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



# DGK (S-PDSO-G8)

# PLASTIC SMALL OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



D (R-PDSO-G14)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
   E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



A. An integration of the information o

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# D0008A



# **PACKAGE OUTLINE**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



#### NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



# D0008A

# **EXAMPLE BOARD LAYOUT**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# D0008A

# **EXAMPLE STENCIL DESIGN**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (https://www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2021, Texas Instruments Incorporated